

Search Notes

Application/Control No.

10/625,209

Examiner

Mark A. Mais

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	310 316	3/18/2007	MAM
	319-322		
	328 395.1		
	395.21		
	395.4		
	395.41		
	395.42		
	431		
455	12.1 427		
	430		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See Inventorship Search	3/18/2007	MAM
See Attached electronic Search	3/18/2007	MAM